

# DATA SHEET

**NEC**

## MOS INTEGRATED CIRCUIT ***μPD431016L***

### 1 M-BIT CMOS FAST STATIC RAM 64 K-WORD BY 16-BIT

#### Description

The *μPD431016L* is a high speed, low power, 1, 048, 576 bits (65, 536 words by 16 bits) CMOS static RAM. Operating supply voltage is 3.3 V ± 0.3 V. The *μPD431016L* are packed in 44-pin plastic SOJ.

#### Features

- 65, 536 words by 16 bits organization
- Fast access time 17, 20 ns (MAX.)
- Byte data control: LB (I/O1 to I/O8), UB (I/O9 to I/O16)
- Output Enable input for easy application
- Single +3.3 V power supply

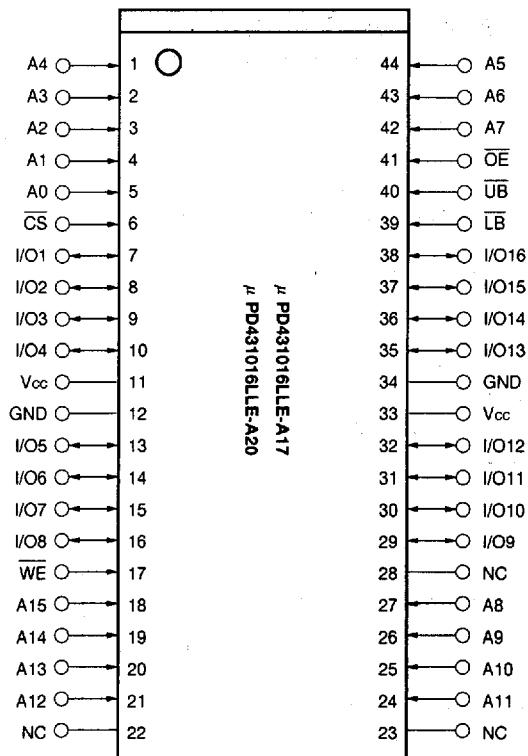
#### Ordering Information

Part number	Package	Access time ns (MAX.)	Operating supply voltage	Supply current mA (MAX.)	
				At operating	At standby
<i>μPD431016LLE-A17</i>	44-pin plastic SOJ (400 mil)	17	3.3 V ± 0.3 V	180	5
		20		160	

The information in this document is subject to change without notice.

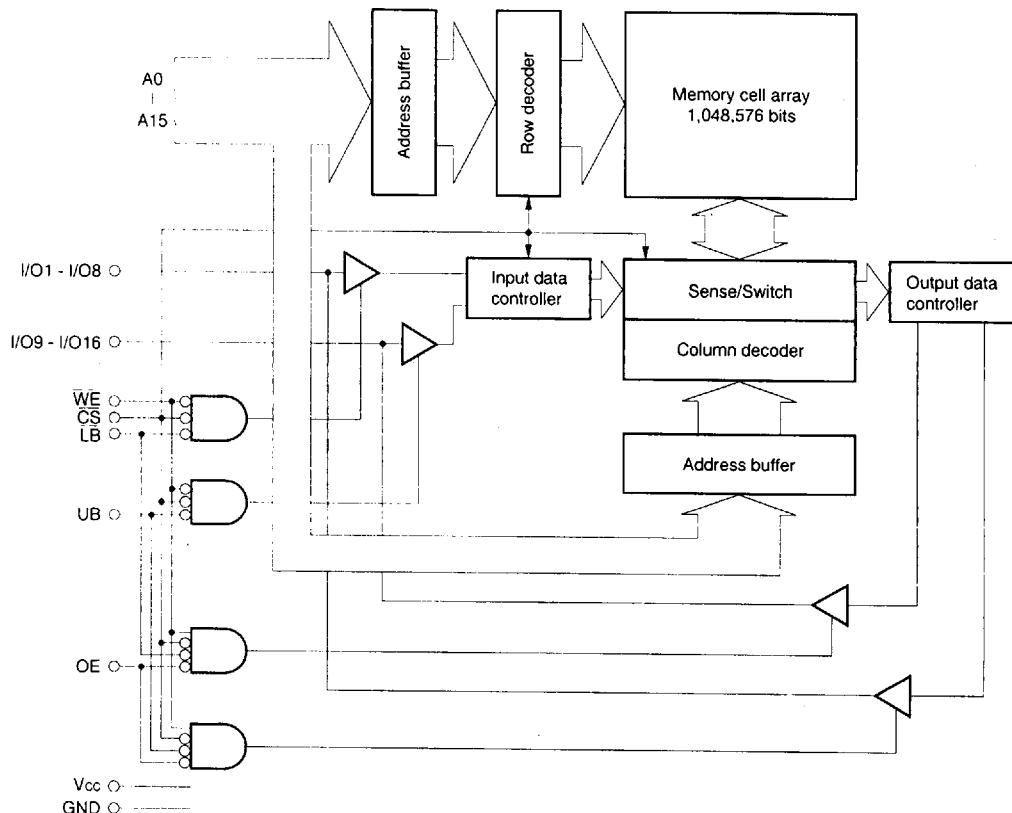
## Pin Configuration (Marking Side)

44-pin plastic SOJ (400 mil)



- A0 - A15 : Address Inputs
- I/O1 - I/O16 : Data Inputs/Outputs
- CS : Chip Select
- WE : Write Enable
- OE : Output Enable
- LB, UB : Byte data select
- Vcc : Power supply
- GND : Ground
- NC : No Connection

## Block Diagram



## Truth Table

<b>CS</b>	<b>OE</b>	<b>WE</b>	<b>LB</b>	<b>UB</b>	Mode	I/O		Supply current
						I/O1 - I/O8	I/O9 - I/O16	
H	x	x	x	x	Not selected	High impedance	High impedance	I <sub>SS</sub>
L	L	H	L	L	Read	D <sub>out</sub>	D <sub>out</sub>	I <sub>CC</sub>
			L	H		D <sub>out</sub>	High impedance	
			H	L		High impedance	D <sub>out</sub>	
L	x	L	L	L	Write	D <sub>IN</sub>	D <sub>IN</sub>	I <sub>CC</sub>
			L	H		D <sub>IN</sub>	High impedance	
			H	L		High impedance	D <sub>IN</sub>	
L	H	H	x	x	Output disable	High impedance	High impedance	
L	x	x	H	H		High impedance	High impedance	

Remark x : Don't care

## Electrical Characteristics

### Absolute Maximum Ratings

Parameter	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	-0.5 Note to +5.0	V
Input/Output voltage	V <sub>T</sub>	-0.5 Note to V <sub>CC</sub> +0.5	V
Operating ambient temperature	T <sub>A</sub>	0 to +70	°C
Storage temperature	T <sub>STG</sub>	-55 to +125	°C

Note -3.0 V (MIN.) (Pulse width: 10 ns)

**Caution** Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational sections of this specification. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

### Recommended Operating Conditions

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Supply voltage	V <sub>CC</sub>	3.0	3.3	3.6	V
High level input voltage	V <sub>IH</sub>	2.0		V <sub>CC</sub> +0.5	V
Low level input voltage	V <sub>IL</sub>	-0.5 Note		+0.8	V
Operating ambient temperature	T <sub>A</sub>	0		+70	°C

Note -3.0 V (MIN.) (Pulse width: 10 ns)

**DC Characteristics (Recommended operating conditions unless otherwise noted)**

Parameter	Symbol	Test conditions		MIN.	TYP.	MAX.	Unit
Input leakage current	I <sub>LI</sub>	$V_{IN} = 0 \text{ V}$ to $V_{CC}$		-2		+2	$\mu\text{A}$
I/O leakage current	I <sub>LO</sub>	$V_{IO} = 0 \text{ V}$ to $V_{CC}$ , $\overline{CS} = V_{IH}$ or $\overline{OE} = V_{IH}$ or $\overline{WE} = V_{IL}$ or $\overline{LB} = V_{IH}$ or $\overline{UB} = V_{IH}$		-2		+2	$\mu\text{A}$
Operating supply current	I <sub>CC</sub>	$\overline{CS} = V_{IL}$ , $I_{IO} = 0 \text{ mA}$		Cycle time: 17 ns		180	$\text{mA}$
Standby supply current	I <sub>SB</sub>	$\overline{CS} = V_{IH}$ , $V_{IN} = V_{IH}$ or $V_{IL}$				20	
	I <sub>SBI</sub>	$\overline{CS} \geq V_{CC} - 0.2 \text{ V}$ , $V_{IN} \leq 0.2 \text{ V}$ or $V_{IN} \geq V_{CC} - 0.2 \text{ V}$				5	
High level output voltage	V <sub>OH</sub>	$I_{OH} = -2 \text{ mA}$		2.4			V
Low level output voltage	V <sub>OL</sub>	$I_{OL} = 4 \text{ mA}$				0.4	V

**Remark**  $V_{IN}$ : Input voltage

**Capacitance ( $T_A = +25^\circ\text{C}$ ,  $f = 1 \text{ MHz}$ )**

Parameter	Symbol	Test conditions		MIN.	TYP.	MAX.	Unit
Input capacitance	C <sub>IN</sub>	$V_{IN} = 0 \text{ V}$				6	pF
Input/Output capacitance	C <sub>IO</sub>	$V_{IO} = 0 \text{ V}$				8	pF

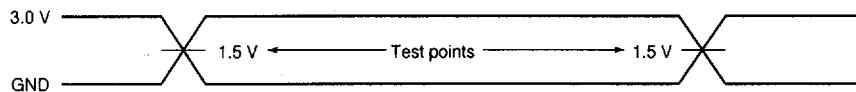
**Remarks 1.**  $V_{IN}$ : Input voltage

2. These parameters are periodically sampled and not 100 % tested.

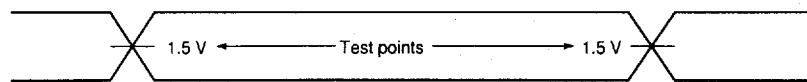
### AC Characteristics (Recommended operating conditions unless otherwise noted)

#### AC Test Conditions

**Input waveform (Rise/fall time  $\leq 3$  ns)**



**Output waveform**

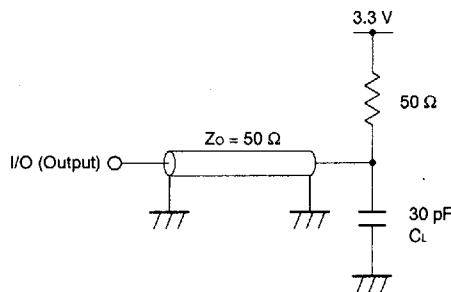


#### Output load

AC Characteristics directed with the note should be measured with the output load shown in **Figure 1** or **Figure 2**.

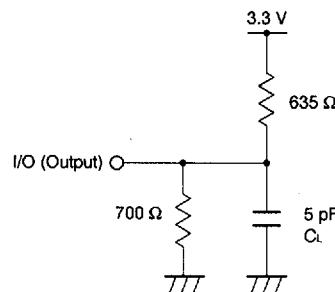
**Figure 1**

(For t<sub>AA</sub>, t<sub>ACS</sub>, t<sub>OE</sub>, t<sub>ABD</sub>, t<sub>OH</sub>)



**Figure 2**

(For t<sub>CLZ</sub>, t<sub>OLZ</sub>, t<sub>BLZ</sub>, t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>BHZ</sub>, t<sub>WHZ</sub>, t<sub>OW</sub>)



**Remark** C<sub>L</sub> includes capacitances of the probe and jig, and stray capacitances.

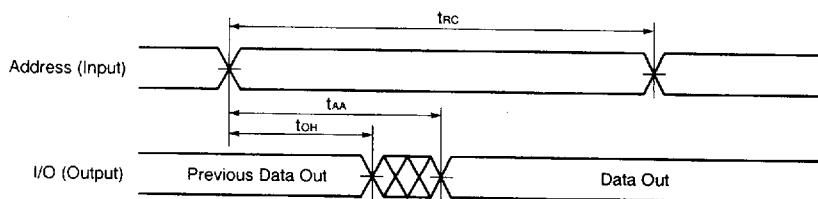
## Read Cycle

Parameter	Symbol	$\mu$ PD431016LLE-A17		$\mu$ PD431016LLE-A20		Unit	Condition
		MIN.	MAX.	MIN.	MAX.		
Read cycle time	t <sub>RC</sub>	17		20		ns	Note 1.
Address access time	t <sub>AA</sub>		17		20	ns	
$\overline{CS}$ access time	t <sub>ACS</sub>		17		20	ns	
$\overline{OE}$ access time	t <sub>OE</sub>		9		10	ns	
$\overline{LB}$ , $\overline{UB}$ access time	t <sub>ABD</sub>		9		10	ns	
Output hold from address change	t <sub>OH</sub>	4		4		ns	
$\overline{CS}$ to output in low impedance	t <sub>CLZ</sub>	4		4		ns	
$\overline{OE}$ to output in low impedance	t <sub>OLZ</sub>	1		1		ns	
$\overline{LB}$ , $\overline{UB}$ to output in low impedance	t <sub>BLZ</sub>	1		1		ns	
$\overline{CS}$ to output in high impedance	t <sub>CHZ</sub>		8		9	ns	
$\overline{OE}$ to output hold in high impedance	t <sub>OHZ</sub>		8		9	ns	Note 2.
$\overline{LB}$ , $\overline{UB}$ to output hold in high impedance	t <sub>HZ</sub>		8		9	ns	

Notes 1. See the output load shown in **Figure 1**.

2. See the output load shown in **Figure 2**.

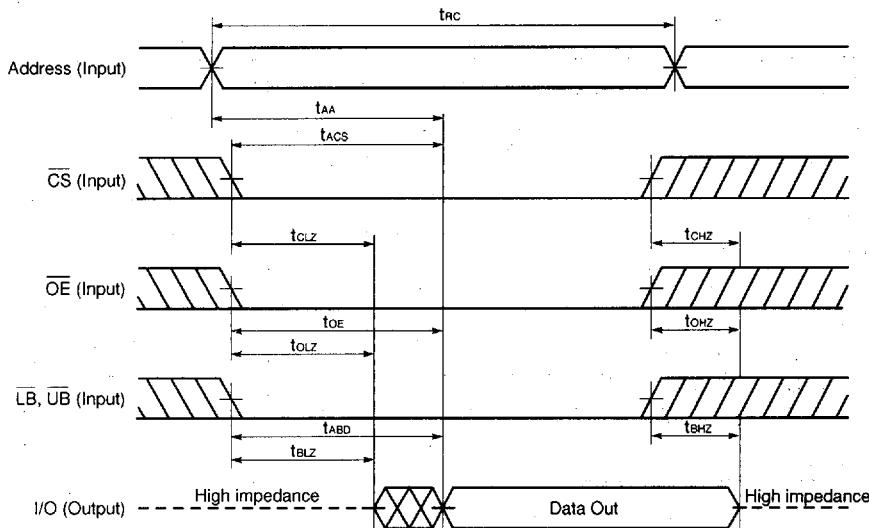
## Read Cycle Timing Chart 1 (Address Access)



Remarks 1. In read cycle,  $\overline{WE}$  should be fixed to high level.

2.  $\overline{CS} = \overline{OE} = \overline{LB}$  (or  $\overline{UB}$ ) = V<sub>IL</sub>

## Read Cycle Timing Chart 2 (CS Access)



**Caution** Address valid prior to or coincident with CS low level input.

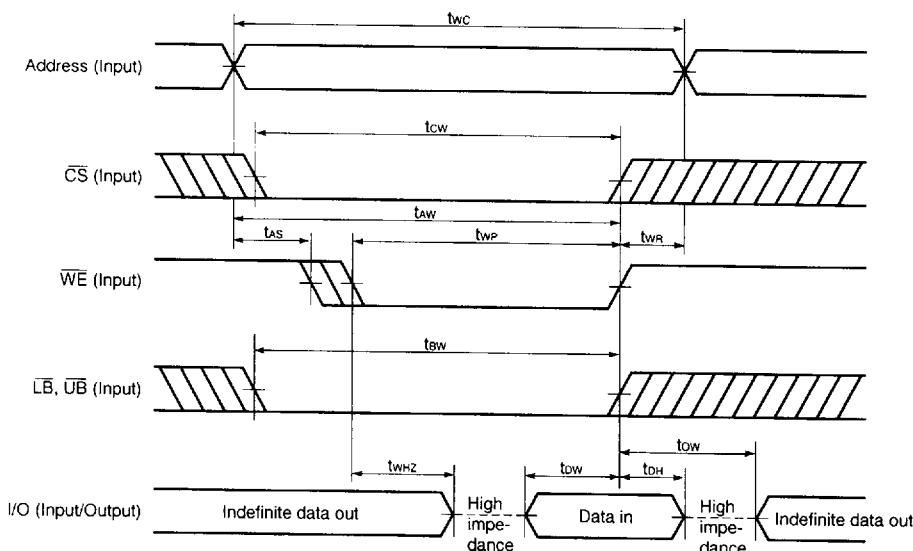
**Remark** In read cycle, WE should be fixed to high level.

## Write Cycle

Parameter	Symbol	$\mu$ PD431016LLE-A17		$\mu$ PD431016LLE-A20		Unit	Condition
		MIN.	MAX.	MIN.	MAX.		
Write cycle time	t <sub>WC</sub>	17		20		ns	
CS to end of write	t <sub>CW</sub>	11		12		ns	
Address valid to end of write	t <sub>AW</sub>	11		12		ns	
Write pulse width	t <sub>WP</sub>	10		10		ns	
LB, UB to end of write	t <sub>BW</sub>	11		12		ns	
Data valid to end of write	t <sub>DW</sub>	9		10		ns	
Data hold time	t <sub>DH</sub>	0		0		ns	
Address setup time	t <sub>AS</sub>	0		0		ns	
Write recovery time	t <sub>WR</sub>	0		0		ns	
WE to output in high impedance	t <sub>WHZ</sub>		8		9	ns	Note
Output active from end of write	t <sub>OZ</sub>	3		3		ns	

Note See the output load shown in Figure 2.

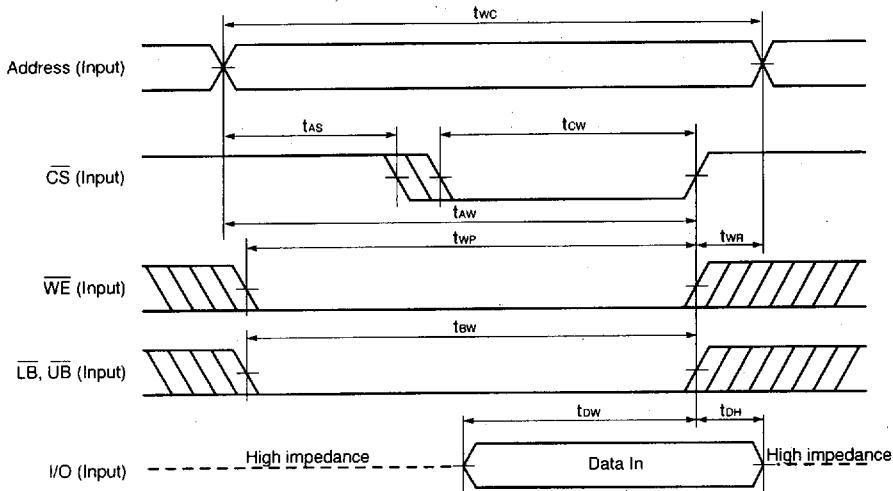
## Write Cycle Timing Chart 1 (WE Controlled)



Caution CS or WE should be fixed to high level during address transition.

- Remarks**
1. Write operation is done during the overlap time of low level CS, low level WE and low level LB (or low level UB).
  2. During  $t_{WHZ}$ , I/O pins are in the output state, therefore the input signals of opposite phase to the output must not be applied.
  3. When WE is at low level, the I/O pins are always high impedance. When WE is at high level, read operation is executed. Therefore OE should be at high level to make the I/O pins high impedance.

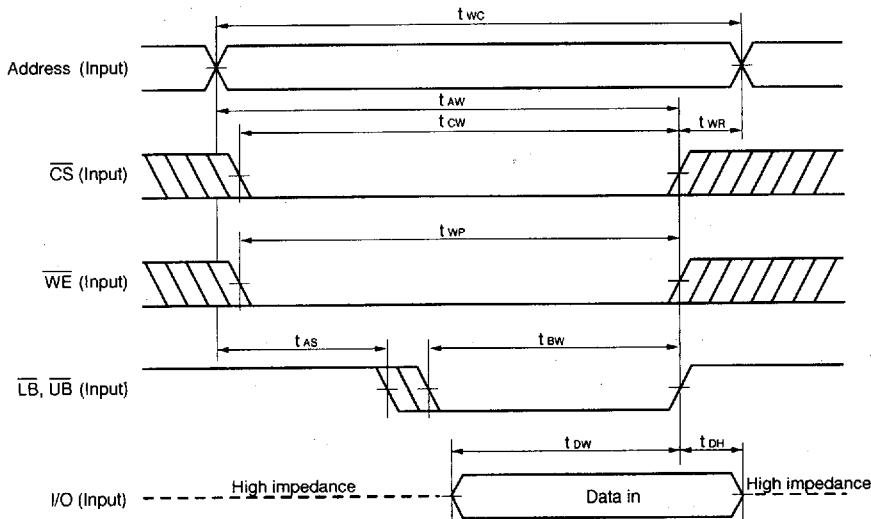
## Write Cycle Timing Chart 2 (CS Controlled)



**Caution** CS or WE should be fixed to high level during address transition.

**Remark** Write operation is done during the overlap time of a low level CS, low level WE and low level LB (or low level UB).

## Write Cycle Timing Chart 3 (LB, UB Controlled)

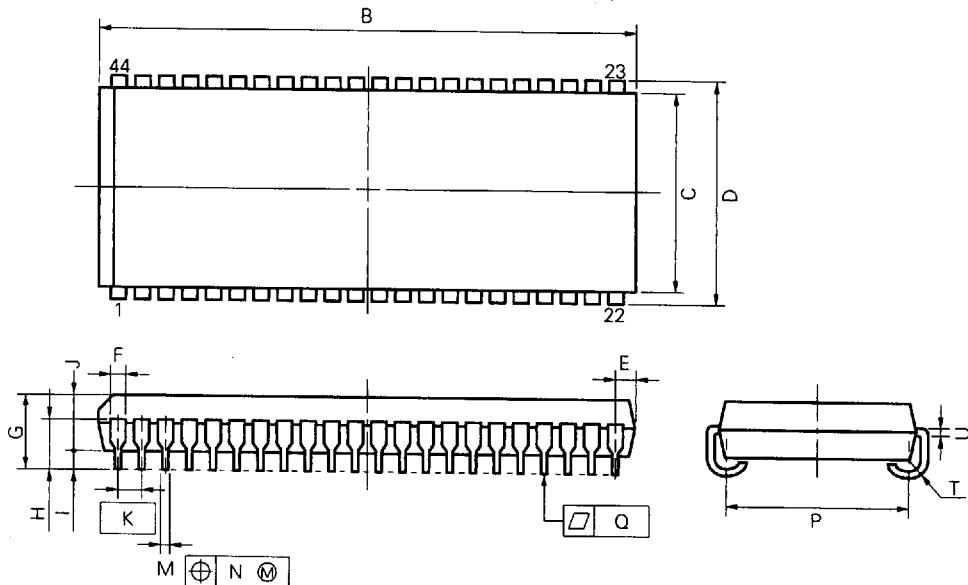


**Caution** CS or WE should be fixed to high level during address transition.

**Remark** Write operation is done during the overlap time of a low level CS, low level WE and low level LB (or low level UB).

## Package Drawing

44 PIN PLASTIC SOJ (400 mil)



P44LE-400A

## NOTE

Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
B	$28.73^{+0.2}_{-0.35}$	$1.131^{+0.008}_{-0.014}$
C	10.16	0.400
D	$11.18 \pm 0.20$	$0.440 \pm 0.008$
E	$1.03 \pm 0.15$	$0.041^{+0.006}_{-0.007}$
F	0.74	0.029
G	$3.5 \pm 0.2$	$0.138 \pm 0.008$
H	$2.3 \pm 0.2$	$0.091^{+0.008}_{-0.009}$
I	0.8 MIN.	0.031 MIN.
J	2.6	0.102
K	1.27 (T.P.)	0.050 (T.P.)
M	$0.40 \pm 0.10$	$0.016^{+0.004}_{-0.005}$
N	0.12	0.005
P	$9.4 \pm 0.20$	$0.370 \pm 0.008$
Q	0.10	0.004
T	R 0.85	R 0.033
U	$0.20^{+0.10}_{-0.05}$	$0.008^{+0.004}_{-0.002}$

**Recommended Soldering Conditions**

Please consult with our sales offices for soldering conditions of the  $\mu$ PD431016L.

**Type of Surface Mount Device**

$\mu$ PD431016LLE: 44-pin plastic SOJ (400 mil)